

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	7	(glass near4 substrate) and interconnect and wafer and chip\$2 and active and bump\$2 and (flip or turn) and dic\$4 and dril\$4 and hol\$2 and via and plug and scale and package	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/01 08:40
S2	0	(glass near4 substrate) and interconnect and wafer and chip\$2 and active and bump\$2 and (flip or turn) and dic\$4 and dril\$4 and hol\$2 and via and plug and scale and package and "indium tin oxide" and eutectic	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/14 13:50
S3	4	(glass near4 substrate) and interconnect and wafer and chip\$2 and active and bump\$2 and (flip or turn) and dic\$4 and dril\$4 and hol\$2 and via and plug and scale and package and "indium tin oxide"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/14 13:50
S4	0	(glass near4 substrate) and interconnect and wafer and chip\$2 and active and bump\$2 and (flip or turn) and dic\$4 and dril\$4 and hol\$2 and via and plug and scale and package and "indium tin oxide" and ACF	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/14 13:50
S5	4	(glass near4 substrate) and interconnect and wafer and chip\$2 and active and bump\$2 and (flip or turn) and dic\$4 and dril\$4 and hol\$2 and via and plug and scale and package and "indium tin oxide"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 10:48
S6	0	"glass substrate" near8 interconnect and (bump or ball) and chips and wafer and dic\$4 and hole and (via near8 plug) and (scale near8 package)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 10:52
S7	0	"glass substrate" near8 interconnect and (bump or ball) and chips and wafer and dic\$4 and hole and (via near8 plug)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 10:52

EAST Search History

S8	58	substrate near8 interconnect and (bump or ball) and chips and wafer and dic\$4 and hole and (via near8 plug)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 10:52
S9	58	(substrate near8 interconnect) and (bump or ball) and chips and wafer and dic\$4 and hole and (via near8 plug)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 10:52
S10	47	(substrate near8 interconnect) and (bump or ball) and chips and wafer and dic\$4 and hole and (via near8 plug) and glass	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 10:52
S11	0	(substrate near8 interconnect) and (bump or ball) and chips and wafer and dic\$4 and hole and (via near8 plug) and glass and drill	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 10:53
S12	0	(substrate near8 interconnect) and (bump or ball) and chips and wafer and dic\$4 and hole and (via near8 plug) and glass and scribe	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 10:53
S13	47	(substrate near8 interconnect) and (bump or ball) and chips and wafer and dic\$4 and hole and (via near8 plug) and glass	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 11:06
S14	0	(substrate near8 interconnect) and (bump or ball) and chips and wafer and dic\$4 and hole and (via near8 plug) and glass and "indium tin oxide"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 10:55
S15	6	(substrate near8 interconnect) and (bump or ball) and chips and wafer and dic\$4 and hole and (via near8 plug) and glass and eutectic	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 10:57

EAST Search History

S16	0	(substrate near8 interconnect) and (bump or ball) and chips and wafer and dic\$4 and hole and (via near8 plug) and glass and eutectic and ACF	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 10:56
S17	0	(substrate near8 interconnect) and (bump or ball) and chips and wafer and dic\$4 and hole and (via near8 plug) and glass and eutectic and anisotropic	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 10:57
S18	0	(drill near8 substrate) and interconnect and wafer and chips and bumps and dic\$4 and holes and (via near4 plug)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 11:08
S19	10915	drill and substrate	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 11:50
S20	16	drill and substrate and interconnect and wafer and chips and bumps and dic\$4 and via and plugs	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 11:52
S21	11	drill and substrate and interconnect and wafer and chips and bumps and dic\$4 and via and plugs and (scale near4 package)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 12:00
S22	11	drill and substrate and interconnect and wafer and chips and bumps and dic\$4 and via and plugs and (scale near4 package) and glass	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 11:53
S23	0	drill and substrate and interconnect and wafer and chips and bumps and dic\$4 and via and plugs and (scale near4 package) and glass and "indium tin oxide"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 11:53

EAST Search History

S24	0	drill and substrate and interconnect and wafer and chips and bumps and dic\$4 and via and plugs and (scale near4 package) and glass and scribe	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 11:54
S25	0	drill and substrate and interconnect and wafer and cover and chips and scribe and pads and dic\$4 and (via near4 plugs) and (scale near4 package) and glass	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 11:56
S26	6	drill and substrate and interconnect and wafer and chips and bumps and dic\$4 and via and plugs and (scale near4 package) and scrib\$4 and pads	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 12:55
S27	3	drill and substrate and interconnect and wafer and chips and bumps and dic\$4 and via and plugs and (scale near4 package) and scrib\$4 and pads .clm.	US-PGPUB	OR	ON	2005/09/15 13:18
S28	0	drill and substrate and interconnect and wafer and chips and bumps and dic\$4 and via and plugs and (scale near4 package) and scrib\$4 and pads and (438/106.ccls.)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 13:20
S29	1	drill and substrate and interconnect and wafer and chips and bumps and dic\$4 and via and plugs and (scale near4 package) and scrib\$4 and pads and (438/108.ccls.)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 13:20
S30	3	drill and substrate and interconnect and wafer and chips and bumps and dic\$4 and via and plugs and (scale near4 package) and scrib\$4 and pads and (438/113.ccls.)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/30 12:57
S31	9	"6908784"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/30 12:58

EAST Search History

S32	0	"CSP" and eutectic and "ACF" and plat\$3 and plug\$2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/01 08:42
S33	0	eutectic and "ACF" and plat\$3 and plug\$2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/01 08:42
S34	1482	eutectic and anisotropic	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/01 08:42
S35	190	eutectic and "anisotropic conductive film"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/01 08:42
S36	11	eutectic and "anisotropic conductive film" and "indium tin oxide"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/01 08:43
S37	11	eutectic and "anisotropic conductive film" and "indium tin oxide" and plat\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/01 10:57
S38	0	eutectic and "anisotropic conductive film" and "indium tin oxide" and plat\$3 and plug	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/01 10:57
S39	12747	"CSP"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 12:39

EAST Search History

S40	1235	"CSP" and (glass near4 (substrate or semiconductor or wafer))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:27
S41	135	"CSP" and (glass near4 (substrate or semiconductor or wafer)) and interconnect near4 (substrate or semiconductor or wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 12:41
S42	1125	"CSP" and (glass near4 substrate)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 12:41
S43	7	"CSP" and ((glass near4 substrate) near4 interconnect)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 12:42
S44	5	"CSP" and ((glass near4 substrate) near4 interconnect) and wafer	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 12:42
S45	3	"CSP" and ((glass near4 substrate) near4 interconnect) and wafer and chip\$2 and bump\$2 and flip	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 12:43
S46	1	"CSP" and ((glass near4 substrate) near4 interconnect) and wafer and chip\$2 and bump\$2 and flip and (dic\$4 near4 wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 12:43
S47	1	"CSP" and ((glass near4 substrate) near4 interconnect) and wafer and chip\$2 and bump\$2 and flip and (dic\$4 near4 wafer) and via	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 12:45

EAST Search History

S48	4	"CSP" and ((glass near4 substrate near4 (interconnect or metal)) and wafer and chip\$2 and bump\$2 and flip and (dic\$4 near4 wafer) and via	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 12:46
S49	1	"CSP" and ((glass near4 substrate near4 (interconnect or metal)) and wafer and chip\$2 and bump\$2 and flip and (dic\$4 near4 wafer) and via and (dic\$4 near4 glass)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 12:47
S50	23	"CSP" and ((glass near4 (substrate or plate)) near4 (interconnect or metal)) and eutectic	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 12:48
S51	11	"CSP" and ((glass near4 (substrate or plate)) near4 (interconnect or metal)) and eutectic and wafer	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 12:49
S52	7	"CSP" and ((glass near4 (substrate or plate)) near4 (interconnect or metal)) and eutectic and (dic\$4 near4 wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 12:50
S53	4	"CSP" and ((glass near4 (substrate or plate)) near4 (interconnect or metal)) and eutectic and (dic\$4 near4 wafer) and (dic\$4 near4 substrate)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 12:56
S54	2	"CSP" and ((glass near4 (substrate or plate)) near4 (interconnect or metal)) and eutectic and (dic\$4 near4 wafer) and (dic\$4 near4 substrate) and flip	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 12:51
S55	682	"CSP" and die\$2 and (pad or interconnect) and adhesive and substrate and (solder near4 ball) and via	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 12:57

EAST Search History

S56	36	"CSP" and die\$2 and (pad or interconnect) and adhesive and substrate and (solder near4 ball) and via and (scribe near4 line)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 12:59
S57	7	"CSP" and die\$2 and (pad or interconnect) and adhesive and substrate and (solder near4 ball) and via and (scribe near4 line) and drill\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 13:16
S58	1	"CSP" and die\$2 and (pad or interconnect) and adhesive and substrate and (solder near4 ball) and via and (scribe near4 line) and drill\$4 and (257/734.ccls.)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 14:47
S59	0	"CSP" and die\$2 and (pad or interconnect) and adhesive and substrate and (solder near4 ball) and via and (scribe near4 line) and drill\$4 and (438/106,108,113.ccls.)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/18 14:47
S60	1473	("CSP" or "chip scale package") and (glass near4 (substrate or semiconductor or wafer))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:28
S61	509	("CSP" or "chip scale package") and (glass near4 (substrate or semiconductor or wafer)) and (plurality near4 chip)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:29
S62	451	("CSP" or "chip scale package") and (glass near4 (substrate or semiconductor or wafer)) and ((plurality near4 chip) near8 (wafer or substrate or semiconductor))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:30
S63	159	("CSP" or "chip scale package") and (glass near4 (substrate or semiconductor or wafer)) and ((plurality near4 chip) near8 (wafer or substrate or semiconductor)) and (plurality near4 bump\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:31

EAST Search History

S64	45	("CSP" or "chip scale package") and (glass near4 (substrate or semiconductor or wafer)) and ((plurality near4 chip) near8 (wafer or substrate or semiconductor)) and (plurality near4 bump\$3) and (flip\$4 near8 (wafer or substrate or semiconductor))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:31
S65	12	("CSP" or "chip scale package") and (glass near4 (substrate or semiconductor or wafer)) and ((plurality near4 chip) near8 (wafer or substrate or semiconductor)) and (plurality near4 bump\$3) and (flip\$4 near8 (wafer or substrate or semiconductor)) and interconnect	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:32
S66	45	("CSP" or "chip scale package") and (glass near4 (substrate or semiconductor or wafer)) and ((plurality near4 chip) near8 (wafer or substrate or semiconductor)) and (plurality near4 bump\$3) and (flip\$4 near8 (wafer or substrate or semiconductor)) and connect\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:32
S67	33	("CSP" or "chip scale package") and (glass near4 (substrate or semiconductor or wafer)) and ((plurality near4 chip) near8 (wafer or substrate or semiconductor)) and (plurality near4 bump\$3) and (flip\$4 near8 (wafer or substrate or semiconductor)) and connect\$4 and (dic\$4 or cut)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:33
S68	29	("CSP" or "chip scale package") and (glass near4 (substrate or semiconductor or wafer)) and ((plurality near4 chip) near8 (wafer or substrate or semiconductor)) and (plurality near4 bump\$3) and (flip\$4 near8 (wafer or substrate or semiconductor)) and connect\$4 and ((dic\$4 or cut) near8 (substrate or semiconductor or wafer))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:34

EAST Search History

S69	1	("CSP" or "chip scale package") and (glass near4 (substrate or semiconductor or wafer)) and ((plurality near4 chip) near8 (wafer or substrate or semiconductor)) and (plurality near4 bump\$3) and (flip\$4 near8 (wafer or substrate or semiconductor)) and connect\$4 and ((dic\$4 or cut) near8 (substrate or semiconductor or wafer)) and (drill\$4 near8 wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:35
S70	4	("CSP" or "chip scale package") and (glass near4 (substrate or semiconductor or wafer)) and ((plurality near4 chip) near8 (wafer or substrate or semiconductor)) and (plurality near4 bump\$3) and (flip\$4 near8 (wafer or substrate or semiconductor)) and connect\$4 and ((dic\$4 or cut) near8 (substrate or semiconductor or wafer)) and (drill\$4 near8 (wafer or semiconductor or substrate))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:35
S71	4	("CSP" or "chip scale package") and (glass near4 (substrate or semiconductor or wafer)) and ((plurality near4 chip) near8 (wafer or substrate or semiconductor)) and (plurality near4 bump\$3) and (flip\$4 near8 (wafer or substrate or semiconductor)) and connect\$4 and ((dic\$4 or cut) near8 (substrate or semiconductor or wafer)) and (drill\$4 near8 (wafer or semiconductor or substrate)) and plug	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:36

EAST Search History

S72	4	("CSP" or "chip scale package") and (glass near4 (substrate or semiconductor or wafer)) and ((plurality near4 chip) near8 (wafer or substrate or semiconductor)) and (plurality near4 bump\$3) and (flip\$4 near8 (wafer or substrate or semiconductor)) and connect\$4 and ((dic\$4 or cut) near8 (substrate or semiconductor or wafer)) and (drill\$4 near8 (wafer or semiconductor or substrate)) and plug and (via near4 hole)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:54
S73	2	("CSP" or "chip scale package") and (glass near4 (substrate or semiconductor or wafer)) and ((plurality near4 chip) near8 (wafer or substrate or semiconductor)) and (plurality near4 bump\$3) and (flip\$4 near8 (wafer or substrate or semiconductor)) and connect\$4 and ((dic\$4 or cut) near8 (substrate or semiconductor or wafer)) and "CTE"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:56
S74	2	("CSP" or "chip scale package") and (glass near4 (substrate or semiconductor or wafer)) and ((plurality near4 chip) near8 (wafer or substrate or semiconductor)) and (plurality near4 bump\$3) and (flip\$4 near8 (wafer or substrate or semiconductor)) and connect\$4 and ((dic\$4 or cut) near8 (substrate or semiconductor or wafer)) and ("CTE" or "coefficient of thermal expansion")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:58
S75	137	("CSP" or "chip scale package") and (glass near4 (substrate or semiconductor or wafer)) and ("CTE" or "coefficient of thermal expansion")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:58
S76	437178	("CSP" or "chip scale package") and (glass near4 (substrate or semiconductor or wafer)) and ("CTE" or "coefficient of thermal expansion") and "indium tin oxide" or "ITO"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:59

EAST Search History

S77	5	("CSP" or "chip scale package") and (glass near4 (substrate or semiconductor or wafer)) and ("CTE" or "coefficient of thermal expansion") and ("indium tin oxide" or "ITO")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 07:59
S78	291	(wafer near4 (scale or level)) and (packag\$4 or encapsulat\$4 or encapsulant or epoxy or underfill) and (second near4 (cut or saw))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/01 13:29
S79	47	(wafer near4 (scale or level)) and (packag\$4 or encapsulat\$4 or encapsulant or epoxy or underfill) and (second near4 (cut or saw)) and (glass near4 substrate)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/29 10:16
S80	11	(wafer near4 (scale or level)) and (packag\$4 or encapsulat\$4 or encapsulant or epoxy or underfill) and (second near4 (cut or saw)) and (glass near4 substrate) and interconnect and flip\$4 and wafer	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/01 13:44
S81	14	"6022758"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/01 13:44
S82	1	(wafer near4 (scale or level)) and (packag\$4 or encapsulat\$4 or encapsulant or epoxy or underfill) and (second near4 (cut or saw)) and (glass near4 substrate) and (257/734.ccls.)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/29 10:17